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March 2015

FDD86102

N-Channel Shielded Gate PowerTrench[®] MOSFET 100 V, 36 A, 24 m Ω

Features

- Shielded Gate MOSFET Technology
- Max $r_{DS(on)}$ = 24 m Ω at V_{GS} = 10 V, I_D = 8 A
- Max $r_{DS(on)}$ = 38 m Ω at V_{GS} = 6 V, I_D = 6 A
- High performance trench technology for extremely low r_{DS(on)}
- High power and current handling capability in a widely used surface mount package
- Very low Qg and Qgd compared to competing trench technologies
- Fast switching speed
- 100% UIL tested
- RoHS Compliant

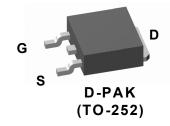


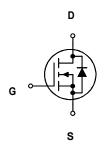
General Description

This N-Channel MOSFET is produced using Fairchild Semiconductor's advanced PowerTrench process that incorporates Shielded Gate technology. This process has been optimized for $r_{DS(on)}$, switching performance and ruggedness.

Application

■ DC - DC Conversion





MOSFET Maximum Ratings T_C = 25 °C unless otherwise noted

Symbol	Param	eter		Ratings	Units
V _{DS}	Drain to Source Voltage			100	V
V _{GS}	Gate to Source Voltage			±20	V
	Drain Current -Continuous	T _C = 25 °C		36	
I _D	-Continuous	T _A = 25 °C	(Note 1a)	8	Α
	-Pulsed		(Note 4)	75	
E _{AS}	Single Pulse Avalanche Energy		(Note 3)	121	mJ
D	Power Dissipation	T _C = 25 °C		62	W
P_D	Power Dissipation	T _A = 25 °C	(Note 1a)	3.1	VV
T _J , T _{STG}	Operating and Storage Junction Tempera	ature Range		-55 to +150	°C

Thermal Characteristics

$R_{\theta JC}$	Thermal Resistance, Junction to Case		2.0	°C/W
$R_{\theta,JA}$	Thermal Resistance, Junction to Ambient	(Note 1a)	40	C/VV

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDD86102	FDD86102	D-PAK(TO-252)	13 "	16 mm	2500 units

Electrical Characteristics T_J = 25 °C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Chara	cteristics					
BV_{DSS}	Drain to Source Breakdown Voltage	I _D = 250 μA, V _{GS} = 0 V	100			V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	I_D = 250 μ A, referenced to 25 °C		67		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 80 V, V _{GS} = 0 V			1	μΑ
I _{GSS}	Gate to Source Leakage Current	V _{GS} = ±20 V, V _{DS} = 0 V			±100	nA

On Characteristics (Note 2)

V _{GS(th)}	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 250 \mu A$	2	3.1	4	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	I_D = 250 μA, referenced to 25 °C		-8.5		mV/°C
		V _{GS} = 10 V, I _D = 8 A		19	24	
r _{DS(on)}	Static Drain to Source On Resistance	$V_{GS} = 6 \text{ V}, I_D = 6 \text{ A}$		26	38	mΩ
` ′		$V_{GS} = 10 \text{ V}, I_D = 8 \text{ A}, T_J = 125 ^{\circ}\text{C}$		33	44	
g _{FS}	Forward Transconductance	V _{DS} = 10 V, I _D = 8 A		21		S

Dynamic Characteristics

C _{iss}	Input Capacitance	. 50.7/.7/	780	1035	pF
Coss	Output Capacitance	─V _{DS} = 50 V, V _{GS} = 0 V, —f = 1 MHz	180	240	pF
C _{rss}	Reverse Transfer Capacitance	1 - 1 101112	15	25	pF
R_g	Gate Resistance		0.4		Ω

Switching Characteristics

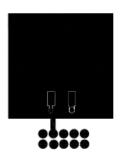
t _{d(on)}	Turn-On Delay Time			7.6	15	ns
t _r	Rise Time	V _{DD} = 50 V, I _D = 8 A,		3	10	ns
t _{d(off)}	Turn-Off Delay Time	$V_{DD} = 50 \text{ V, } I_D = 8 \text{ A,}$ $V_{GS} = 10 \text{ V, } R_{GEN} = 6$	Ω	13.4	24	ns
t _f	Fall Time			2.9	10	ns
Q_{g}	Total Gate Charge	V _{GS} = 0 V to 10 V		13.4	19	nC
Qg	Total Gate Charge	$V_{GS} = 0 \text{ V to 5 V}$	_{DD} = 50 V,	7.6	11	nC
Q_{gs}	Gate to Source Gate Charge	ID	= 8 A	4.0		nC
Q_{gd}	Gate to Drain "Miller" Charge			3.7		nC

Drain-Source Diode Characteristics

V _{SD}	Source to Drain Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = 8 \text{ A}$ (Note 2)	0.8	3 1.3	W
		$V_{GS} = 0 \text{ V}, I_S = 2.6 \text{ A}$ (Note 2)	0.	7 1.2	v
t _{rr}	Reverse Recovery Time	I _E = 8 A, di/dt = 100 A/μs	43	68	ns
Q _{rr}	Reverse Recovery Charge	- 1 - 0 Α, α/αι - 100 Α/μς	43	68	nC

Notes:

^{1.} R_{0JA} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R_{0JC} is guaranteed by design while R_{0JA} is determined by the user's board design.



a. 40 °C/W when mounted on a 1 in² pad of 2 oz copper.



 b. 96 °C/W when mounted on a minimum pad of 2 oz copper.

- 2. Pulse Test: Pulse Width < 300 $\mu\text{s},$ Duty cycle < 2.0%.
- 3. E_{AS} 121 mJ is based on starting T_J = 25 °C, L = 3 mH, I_{AS} = 9 A, V_{DD} = 100 V, V_{GS} = 10 V. 100% test at L = 0.1 mH, I_{AS} = 30 A.
- 4. Pulsed Drain current is tested at 300 µs with 2% duty cycle. For repetitive pulses, the pulse width is limited by the maximum junction temperature.

Typical Characteristics T_J = 25 °C unless otherwise noted

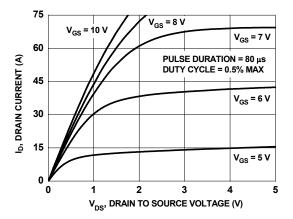


Figure 1. On-Region Characteristics

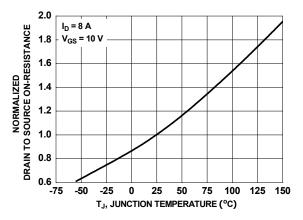


Figure 3. Normalized On-Resistance vs Junction Temperature

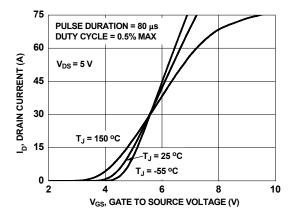


Figure 5. Transfer Characteristics

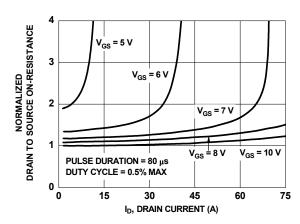


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

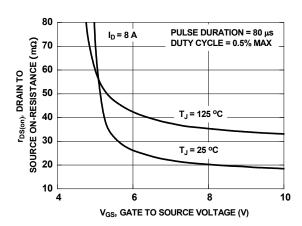


Figure 4. On-Resistance vs Gate to Source Voltage

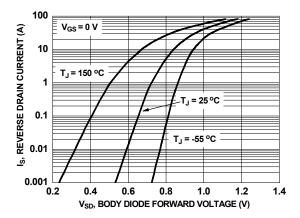


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

Typical Characteristics T_J = 25 °C unless otherwise noted

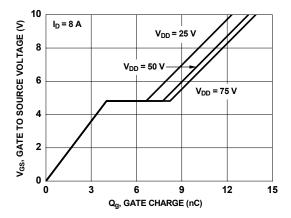


Figure 7. Gate Charge Characteristics

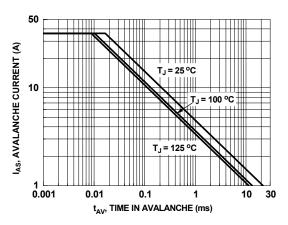


Figure 9. Unclamped Inductive Switching Capability

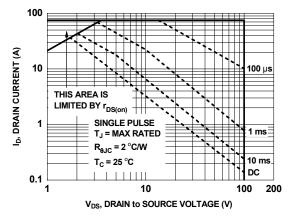


Figure 11. Forward Bias Safe Operating Area

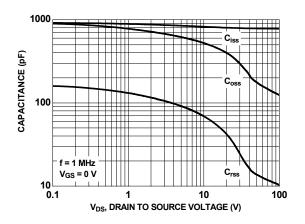


Figure 8. Capacitance vs Drain to Source Voltage

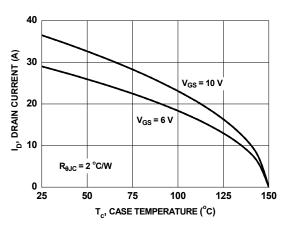


Figure 10. Maximum Continuous Drain Current vs Case Temperature

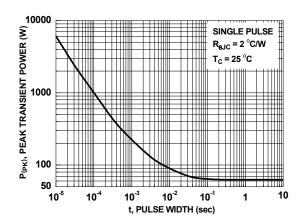


Figure 12. Single Pulse Maximum Power Dissipation

Typical Characteristics T_J = 25 °C unless otherwise noted

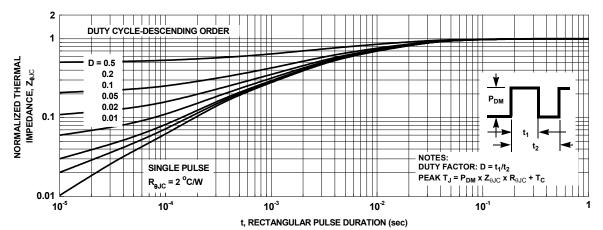


Figure 13. Junction-to-Case Transient Thermal Response Curve



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